

LDPC-in-SSD: Making Advanced Error Correction Codes Work Effectively in Solid State Drives

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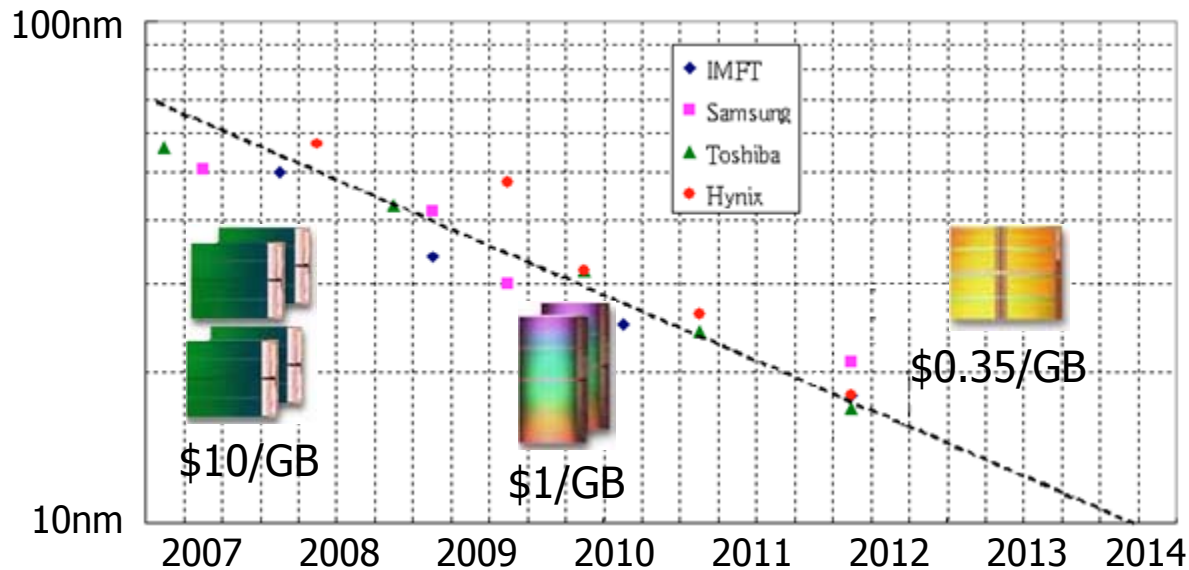
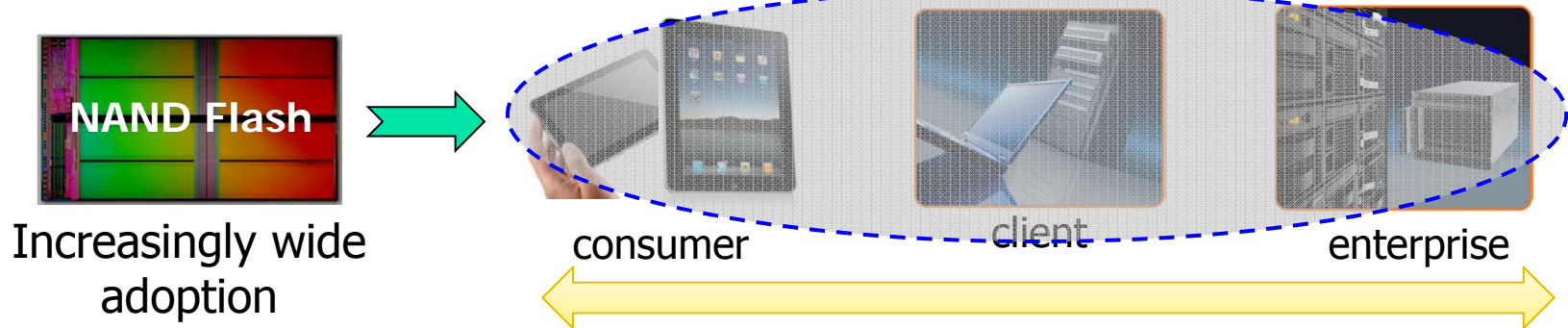
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NAND Flash Memory

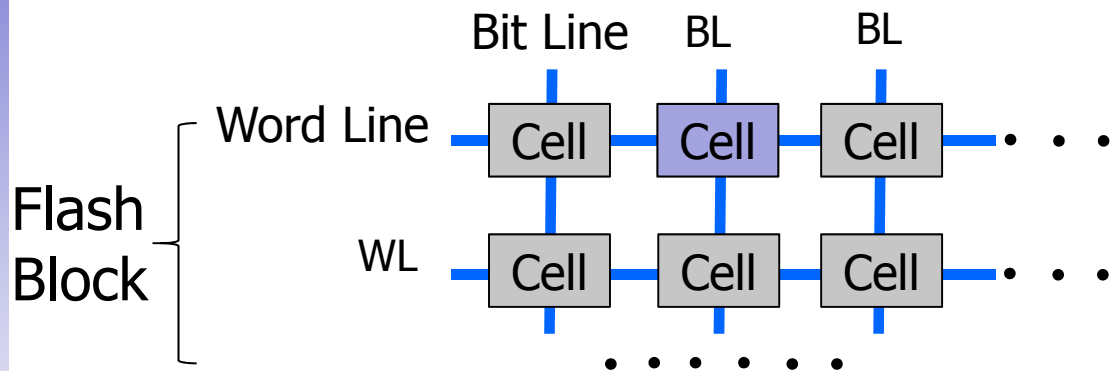
- Increasing Adoptions and Decreasing Cost of NAND Flash Memory



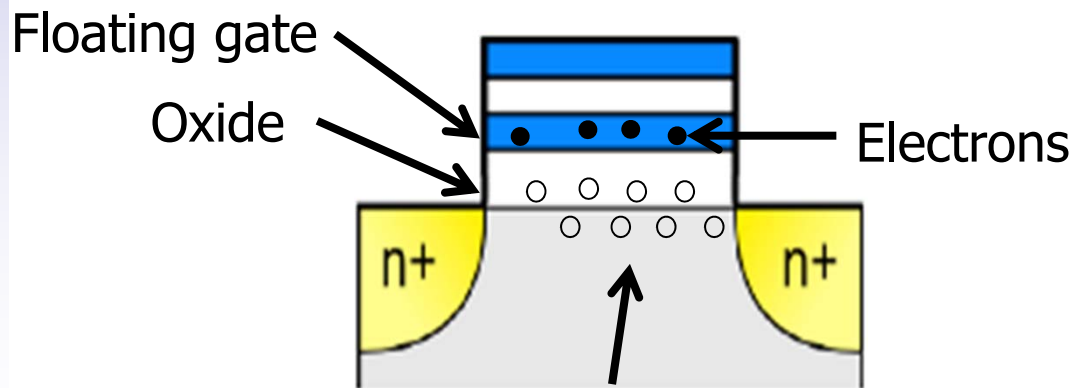
Bit cost reduction

NAND Flash Memory

- Noise in NAND flash memory increases as chip technology scaling continues



- Cell size and distance between cells shrink



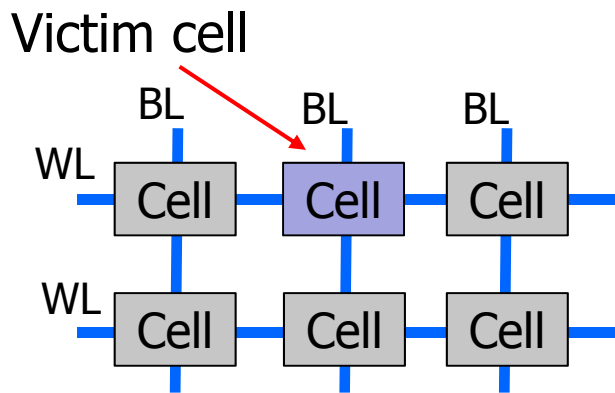
- Oxide layer becomes thinner
- Number of electrons held in floating gate reduced

Charge trap, caused by P/E cycling

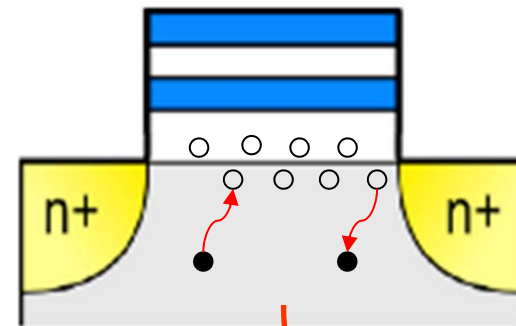
NAND Flash Memory

- Smaller cell, thinner oxide layer and fewer electrons make the flash memory increasingly noisy

Cell-to-cell interference



Random telegraph noise (RTN)



Retention noise

Electrons leaks from the floating gate

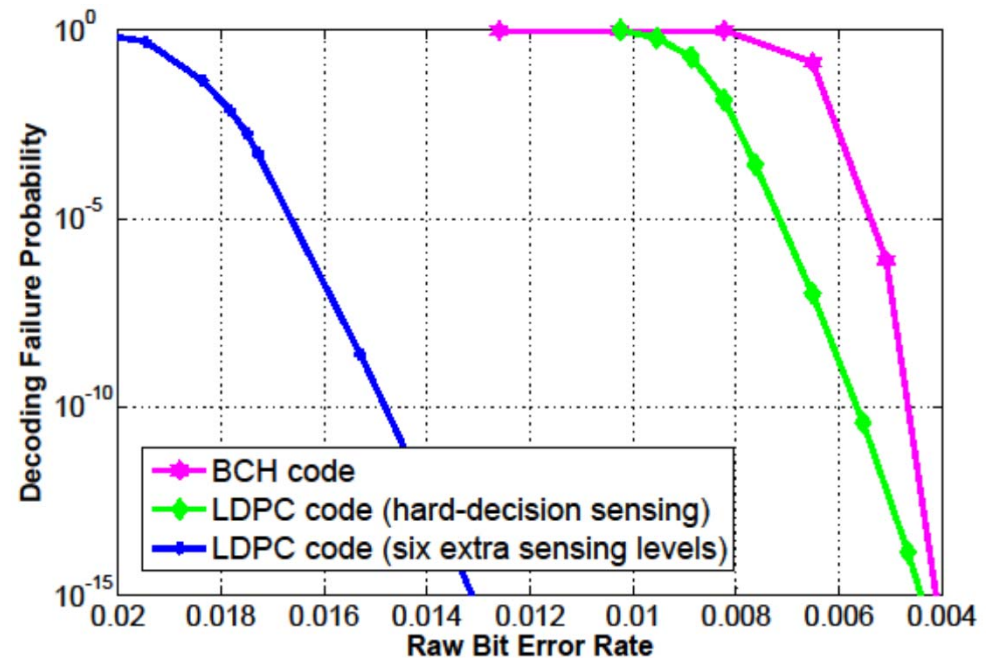


Higher raw
bit error rate

Error Correction Codes in Storage Systems

- Bose-Chaudhuri-Hocquengham (BCH) code
 - A class of cyclic error-correcting codes, invented in 1959, hard-decision decoding, adopted in all SSDs
- Low-density parity-check (LDPC) code
 - A linear error-correcting code, invented by Robert.G.Gallager in 1963 and rediscovered in 1996, hard-decision/soft-decision decoding

Soft-decision LDPC code has a much stronger error correction capability



Error Correction Codes in Storage Systems

- BCH codes' relatively weak error correction capability becomes inadequate
- LDPC code can significantly improve the reliability of SSDs compared to BCH code
- Challenges for adopting LDPC codes in SSDs
 - Designing LDPC codes of good performance
 - Techniques to address the LDPC decoder input initialization problem
 - Minimizing LDPC-induced latency increase in SSDs

Outline

- LDPC code and soft-decision sensing
- Proposed techniques
- Experiment Setup and Preparation
- Experimental Results
- Conclusion

LDPC Code and Soft Sensing

- Hard-decision decoding (BCH, LDPC)
 - Inputs are in binary form
 - Simple hardware implementation
 - Relatively weak error correction capability
- Soft-decision decoding (LDPC)
 - Inputs are quantized to integers
 - Complicated hardware design
 - Strong error correction capability

For LDPC code, its error correction strength strongly depends on the accuracy of the input information which presents the probability information of the data stored in NAND flash memory

LDPC Code and Soft Sensing



1,0,1,1,0,1,0,0,0,1,1,0

Hard-decision

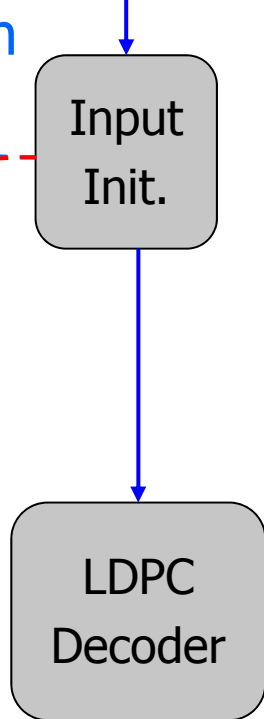
-4,+2,-1,-1,+3,-2,+2,+3,+2,-4,-3,+1

Soft-decision

$$\log \left(\frac{P(y_i | x_i = 0)}{P(y_i | x_i = 1)} \right)$$

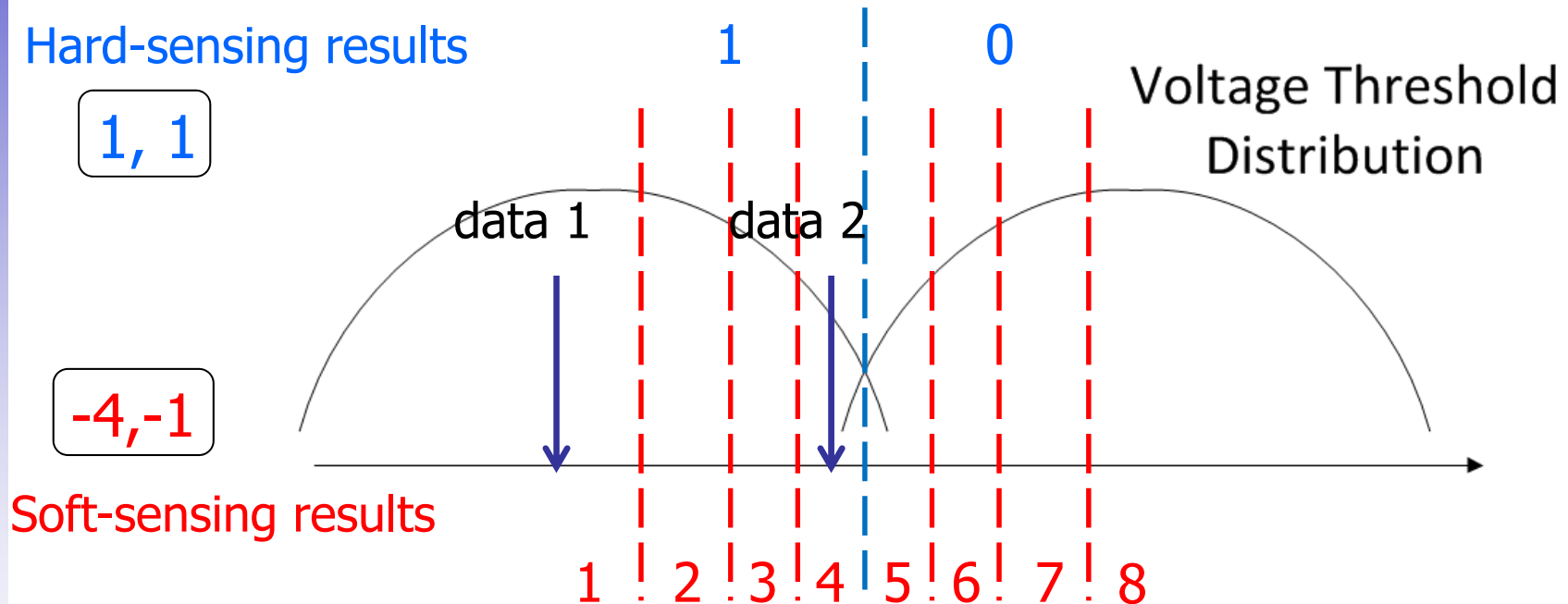
Log-likelihood ratio (LLR)

Positive: 0
Negative: 1
Magnitude presents
the probability



LDPC Code and Soft-sensing

Hard sensing vs. Soft sensing

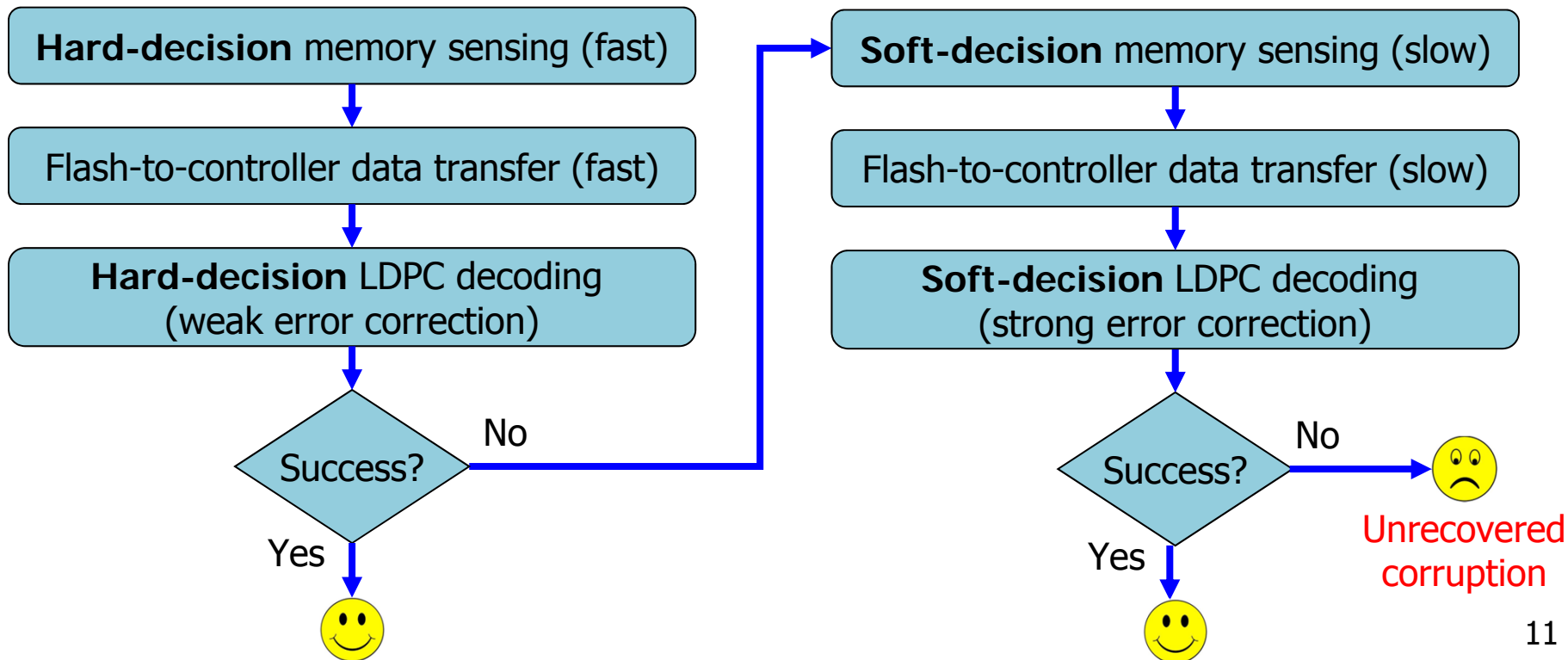


Quantization	1 bit	2 bits	3 bits
Times of Sensing	1	3	7

Soft-decision decoding suffers from **a huge latency**

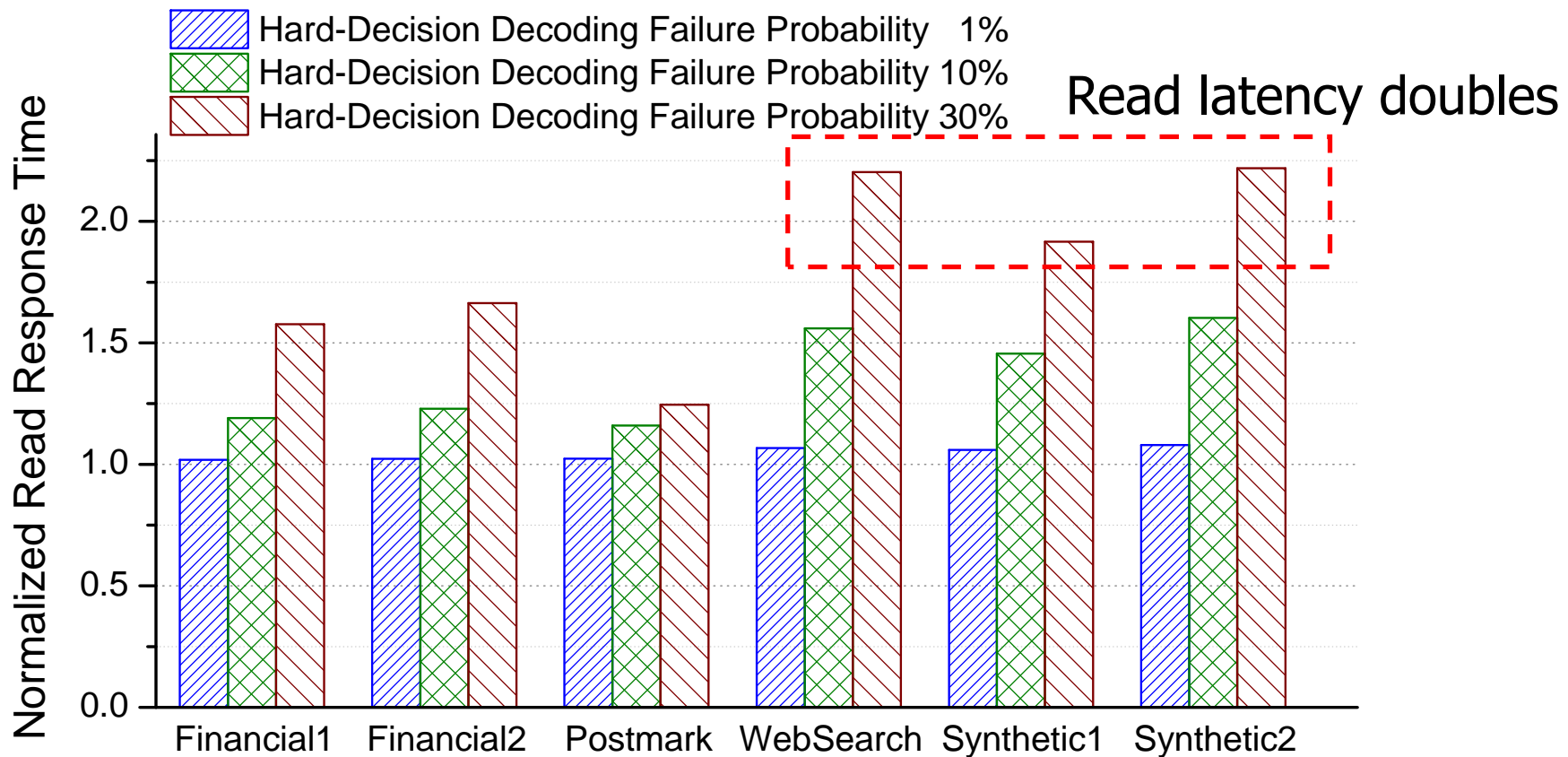
LDPC Code and Soft Sensing

- Large latency of soft-decision sensing and corresponding data transfer to SSD controller is destructive to read performance
- A basic two-step read strategy
 - Hard-decision decoding still works in most of the times



LDPC and Soft Sensing

- Trace-based simulation shows that further improvement is necessary

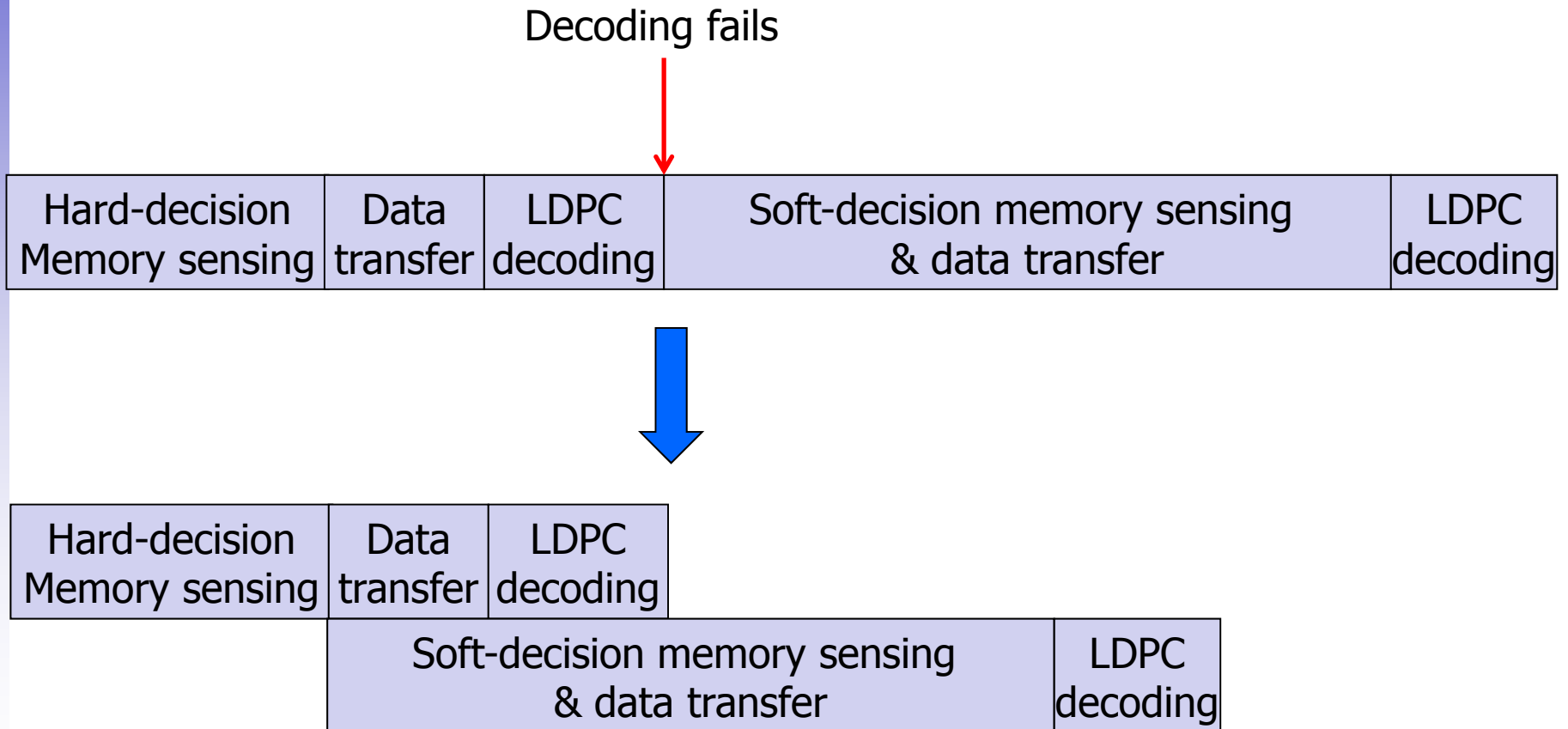


Proposed Techniques

- Two orthogonal aspects to improve read performance
 - Minimize the latency of soft-decision sensing and data transfer
 - Minimize the unnecessary number of high-precision soft-decision sensing
- Our approaches
 - Look-Ahead Memory Sensing
 - Fine-Grained Progressive Sensing and Decoding
 - Data Placement Interleaving

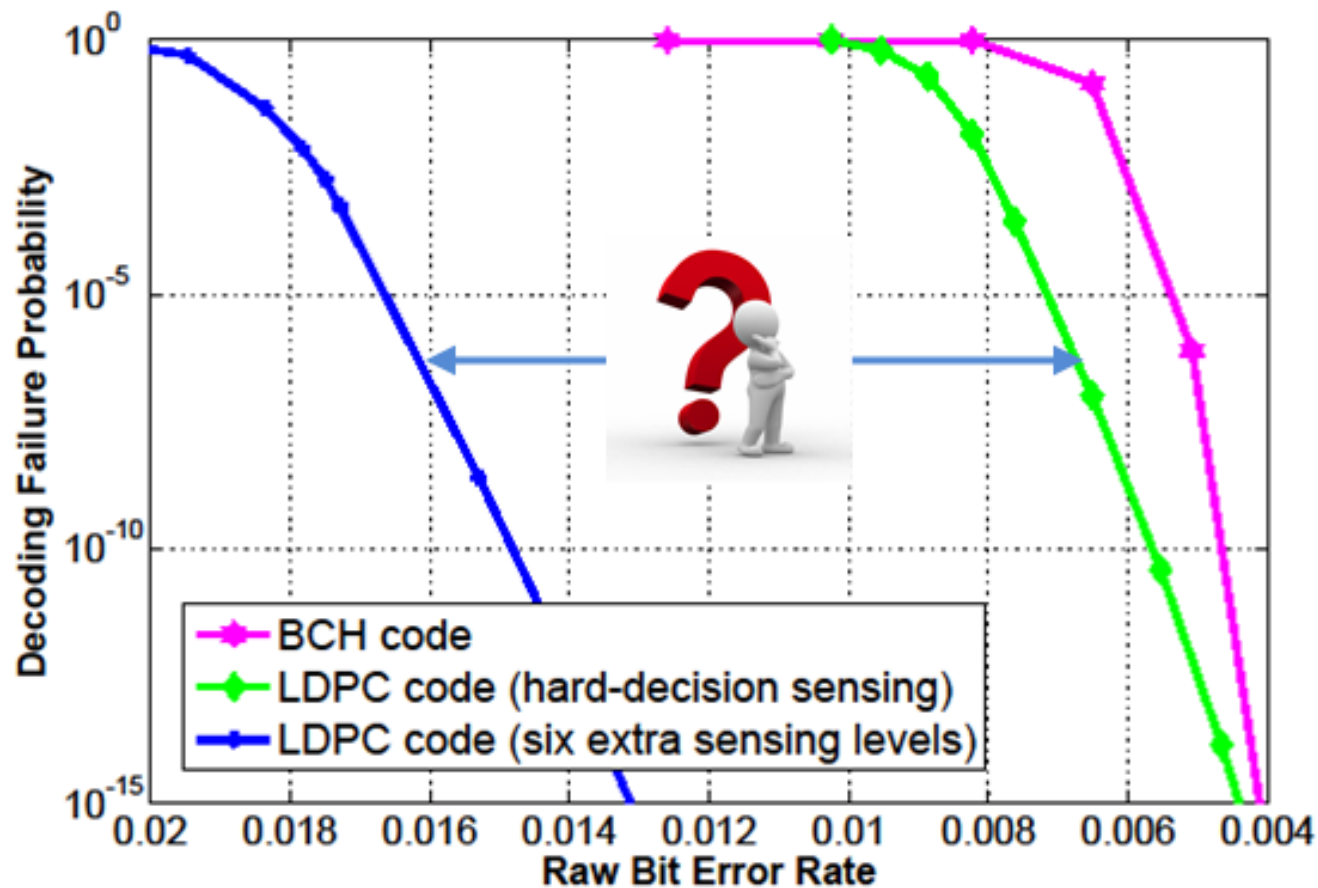
Look-ahead Memory Sensing

- Start soft-decision sensing in advance



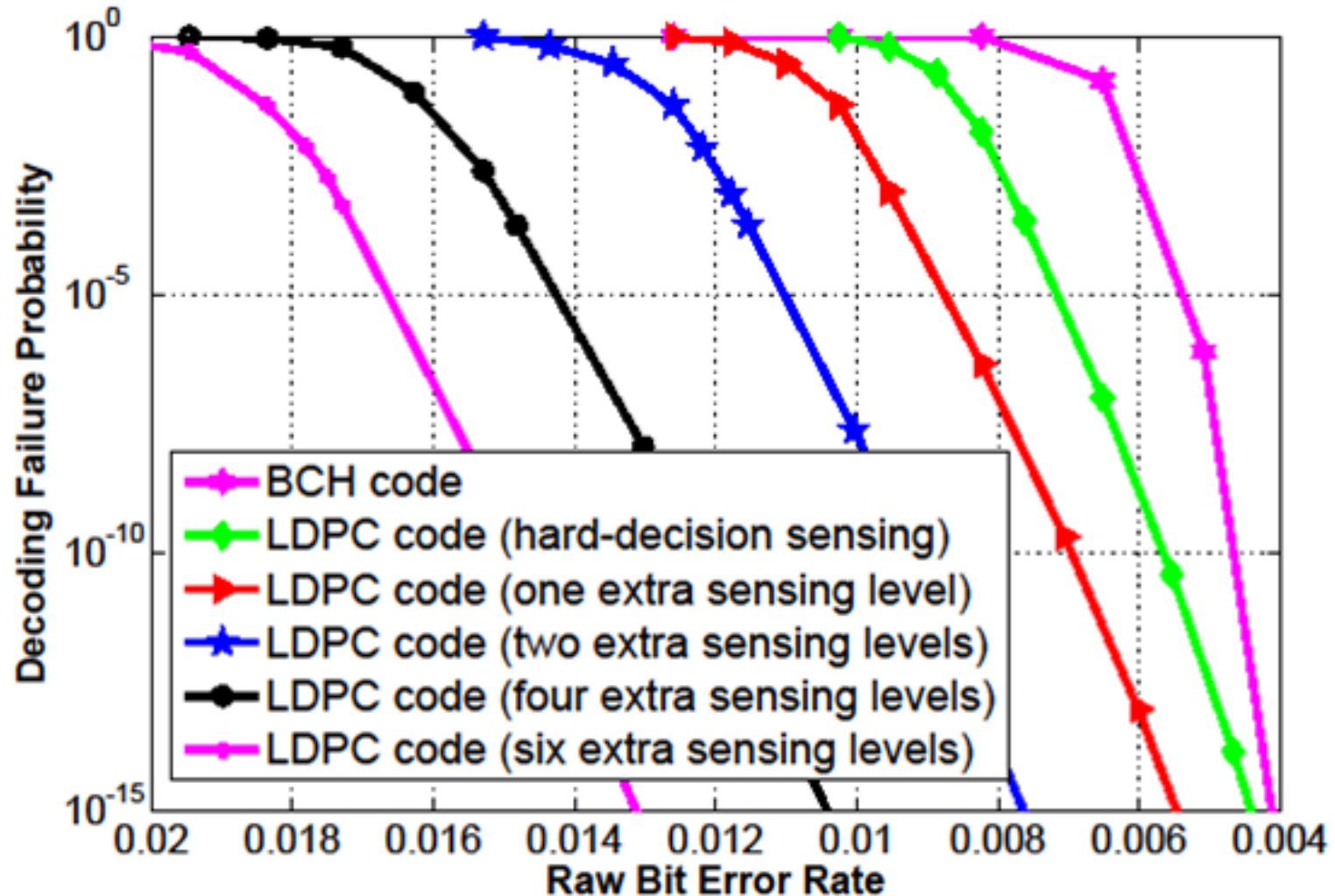
Fine-Grained Progressive Sensing and Decoding

- Why not exploit the trade-off space between latency and error correction capability

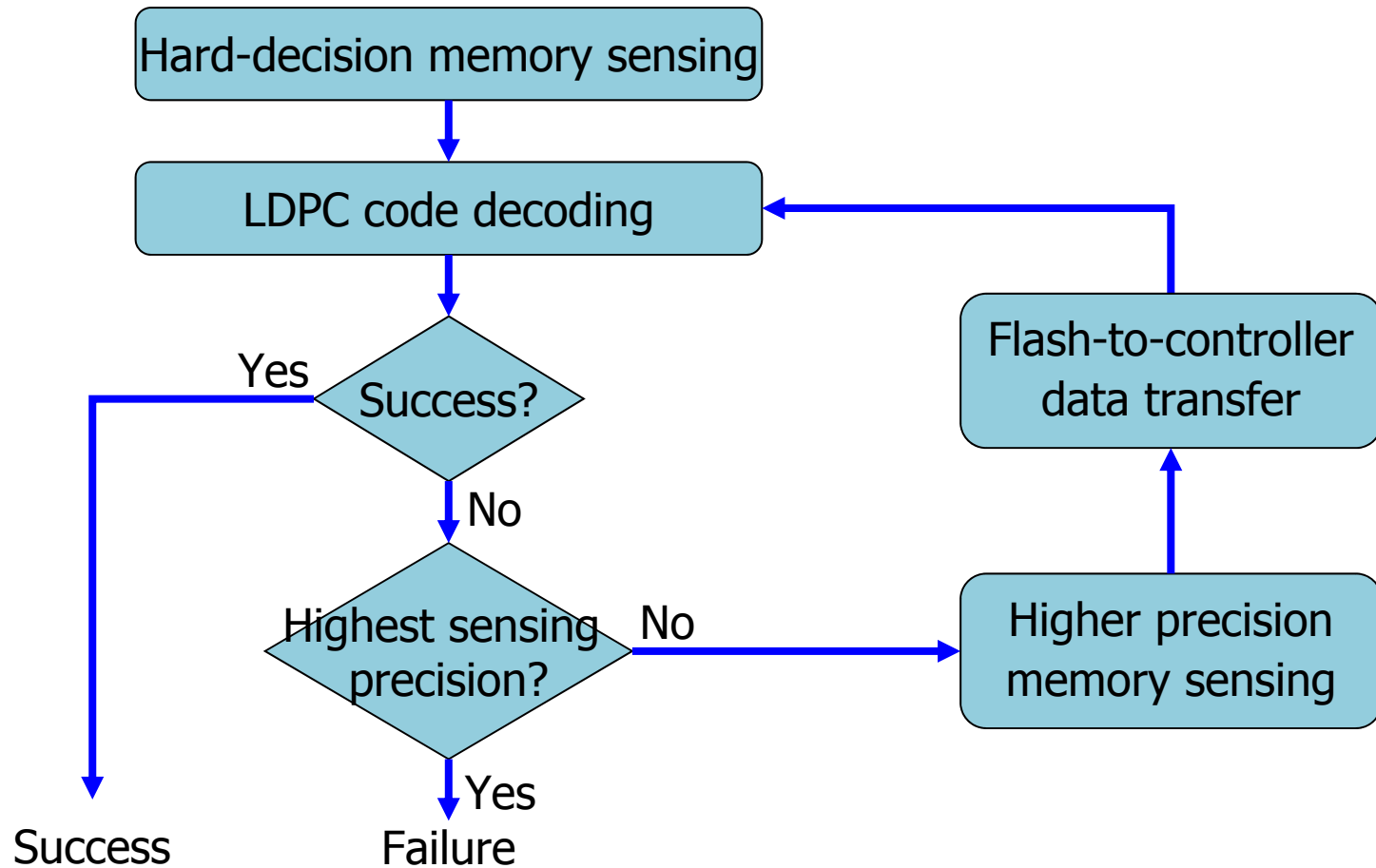


Fine-Grained Progressive Sensing and Decoding

- Fully exploit LDPC's error correction capability



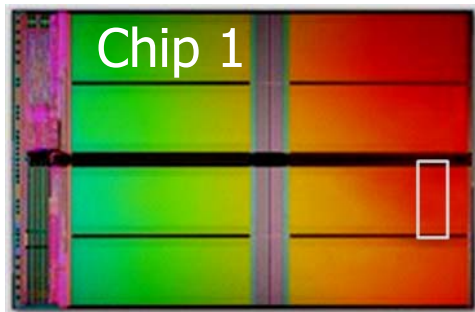
Fine-Grained Progressive Sensing and Decoding



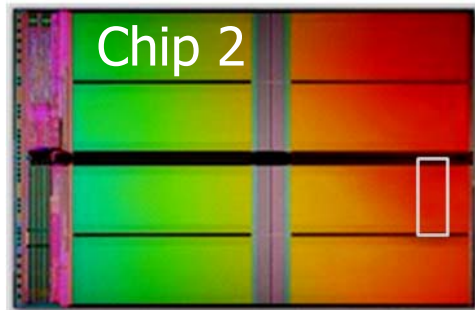
Can be combined with look-ahead memory sensing design strategy

Data Placement Interleaving

- Noticeable reliability variance among different NAND flash memory chips



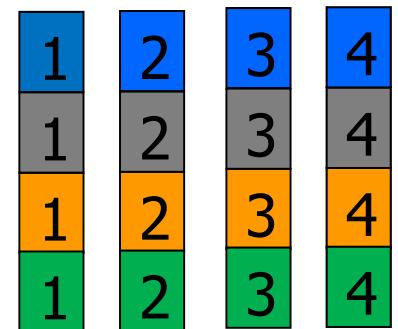
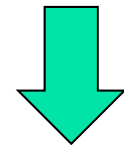
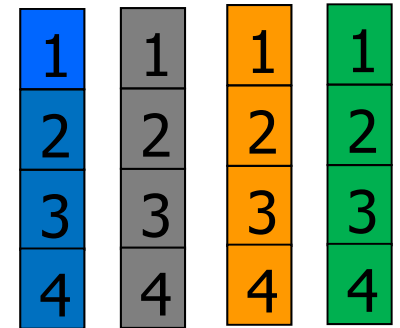
Block 1
Low raw BER



Block 2
High raw BER
Even uncorrectable

Average to avoid
invoking high precision
LDPC decoding

4-way interleaving



Experiment Setup and Preparation

- SSD Simulator: SSD module in DiskSim
- Workload traces: Financial1&2, Postmark, WebSearch, Synthetic workload1&2
- MLC NAND flash memory chip configuration
 - 4KB per page, 64 pages per block, 2048 blocks per plane, 4 planes per die, and 2 dies per chip.
 - 8 chips X 8 channels
 - 200 MBps chip I/O bandwidth
- Separate parameters for upper/lower pages
 - Read/write/erasure latency
 - Page raw bit error rate

Experiment Setup and Preparation

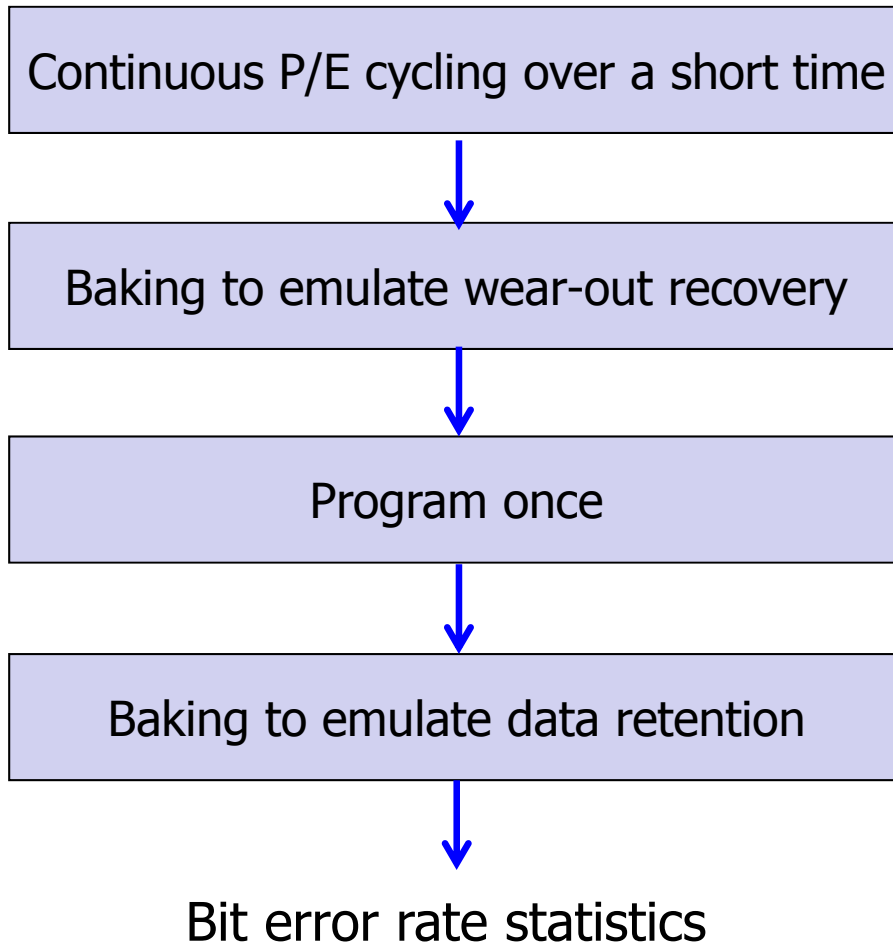
- Our measurement results are based on 25 nm MLC NAND flash chips

	Read	Write
Upper page	55 μ s	1.45 ms
Lower page	41 μ s	121 μ s

- Latency of sensing one extra level is set to 14 μ s
- 10k PE cycles and 1 month retention time

Experiment Setup and Preparation

- Experiment flow to get the BER statistics



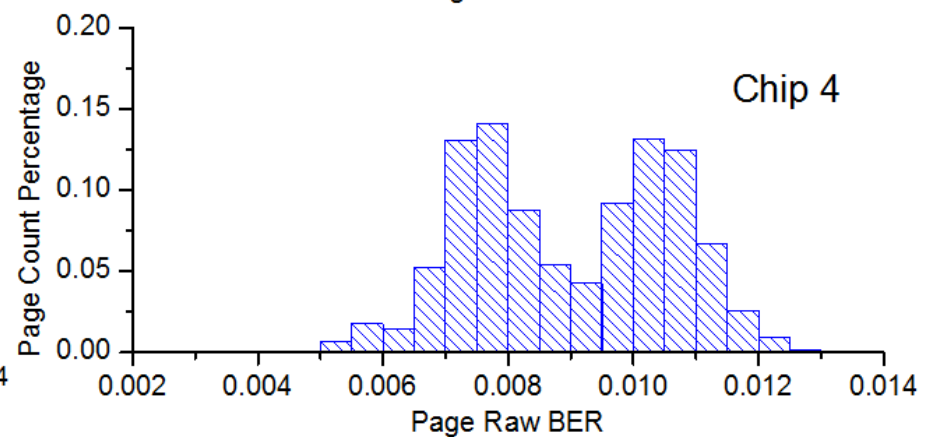
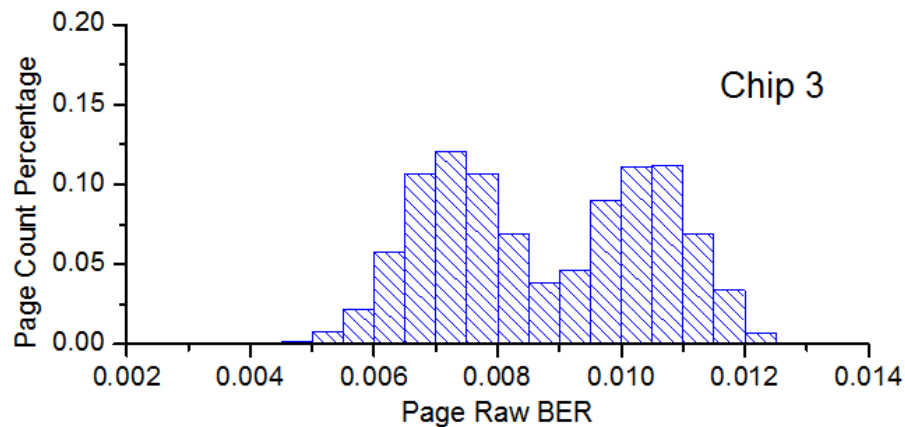
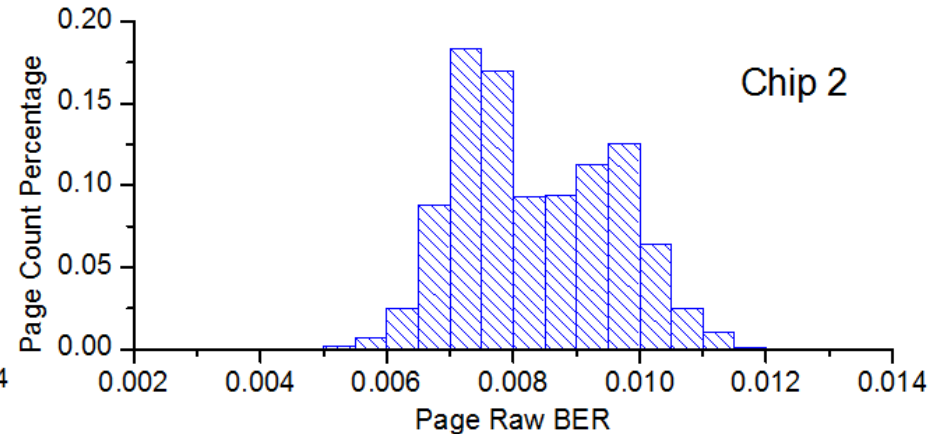
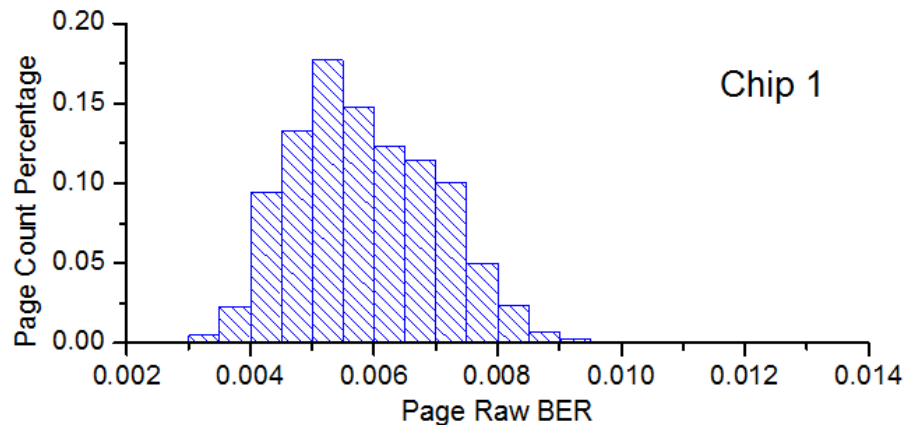
Use Arrhenius law to determine the baking time

$$t_{rc} = A \cdot t_{cyc} \cdot e^{E_A \left(\frac{1}{k \cdot T_{rc}} - \frac{1}{k \cdot T_{cyc}} \right)}$$

$$t_{rt} = t_{cyc} \cdot e^{E_A \left(\frac{1}{k \cdot T_{rt}} - \frac{1}{k \cdot T_{cyc}} \right)}$$

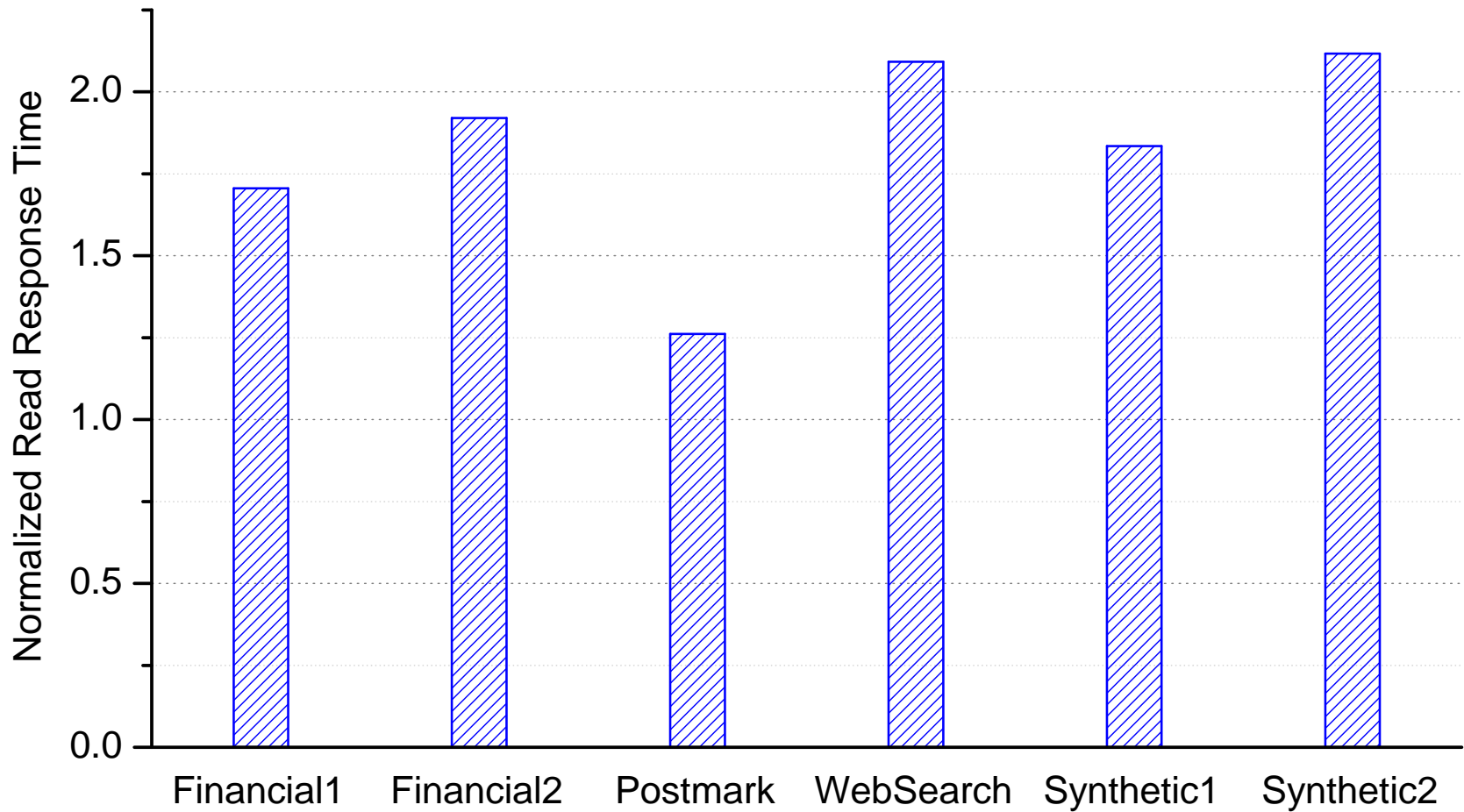
Experiment Setup and Preparation

■ Page raw BER distribution



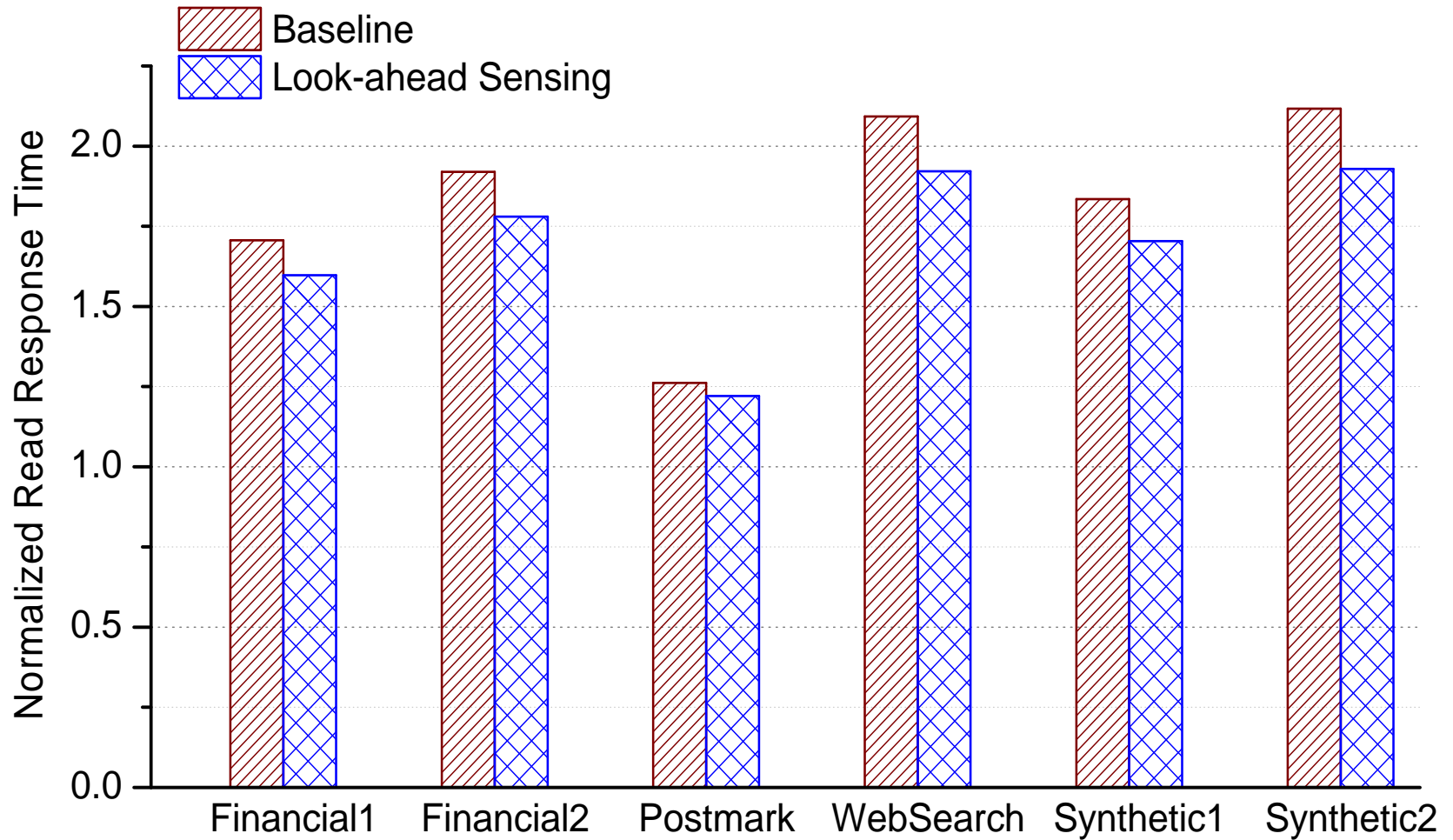
Experimental Results

- Baseline: two-step sensing and decoding strategy



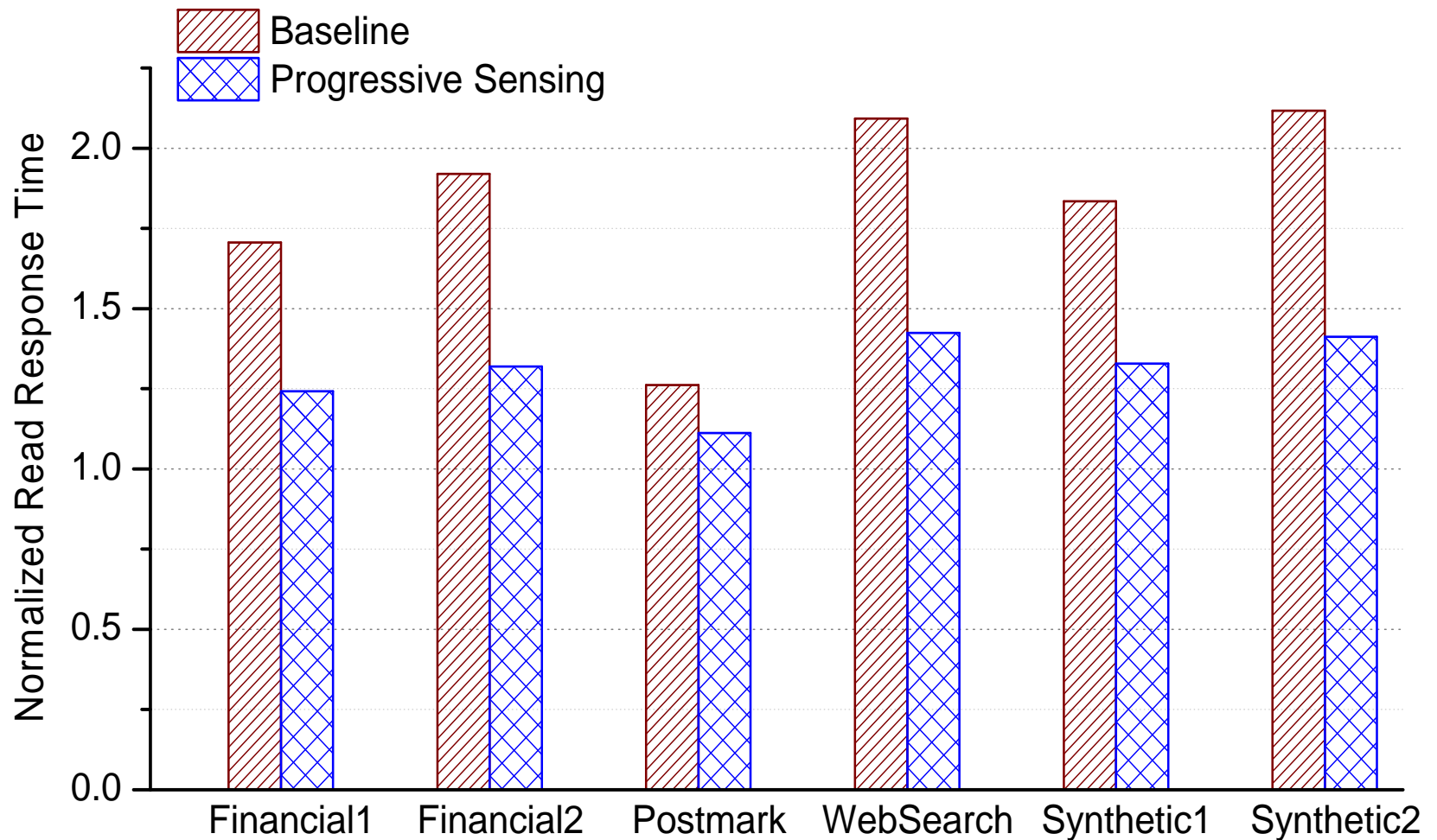
Experimental Results

- Look-ahead memory sensing



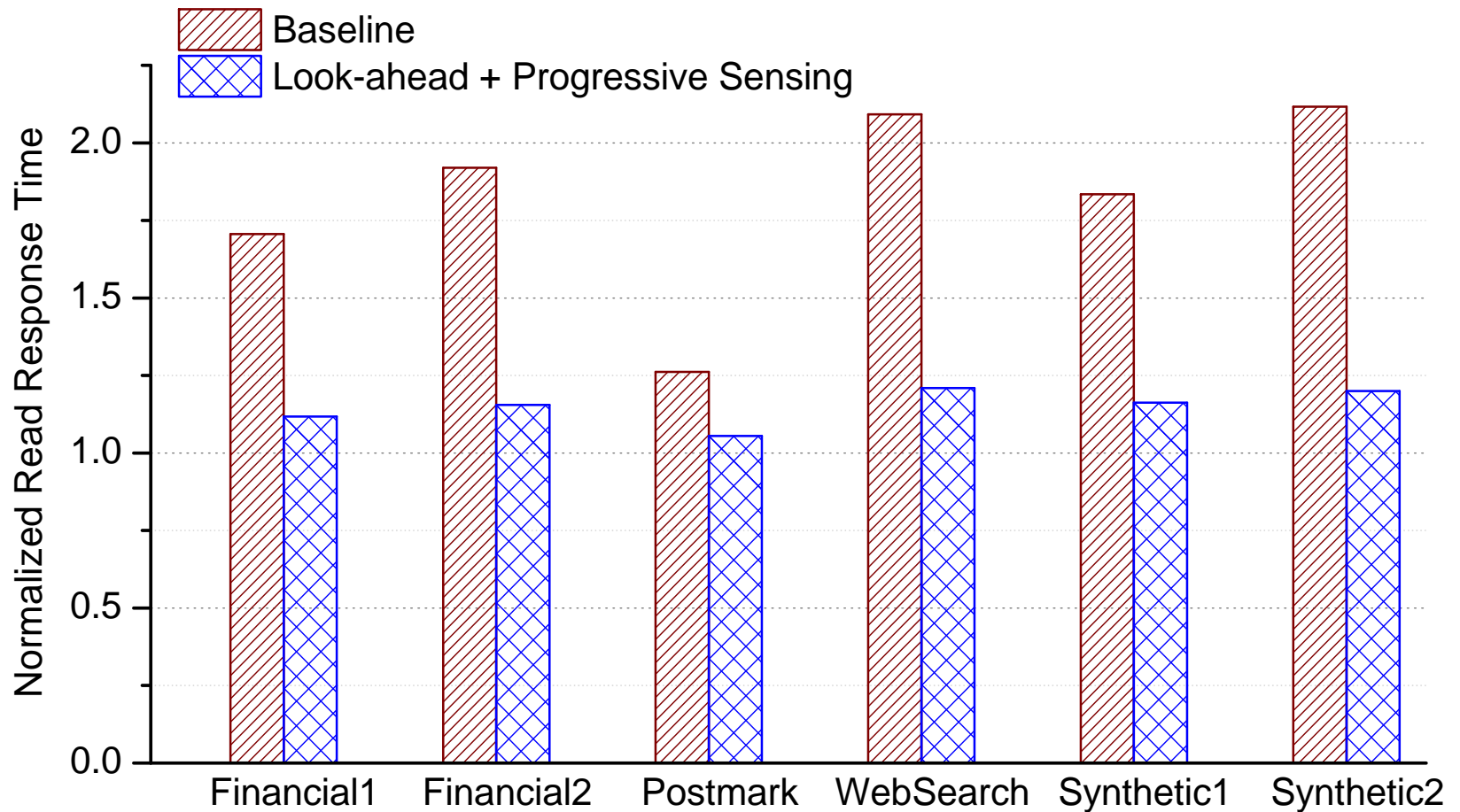
Experimental Results

- Fine-grained progressive sensing



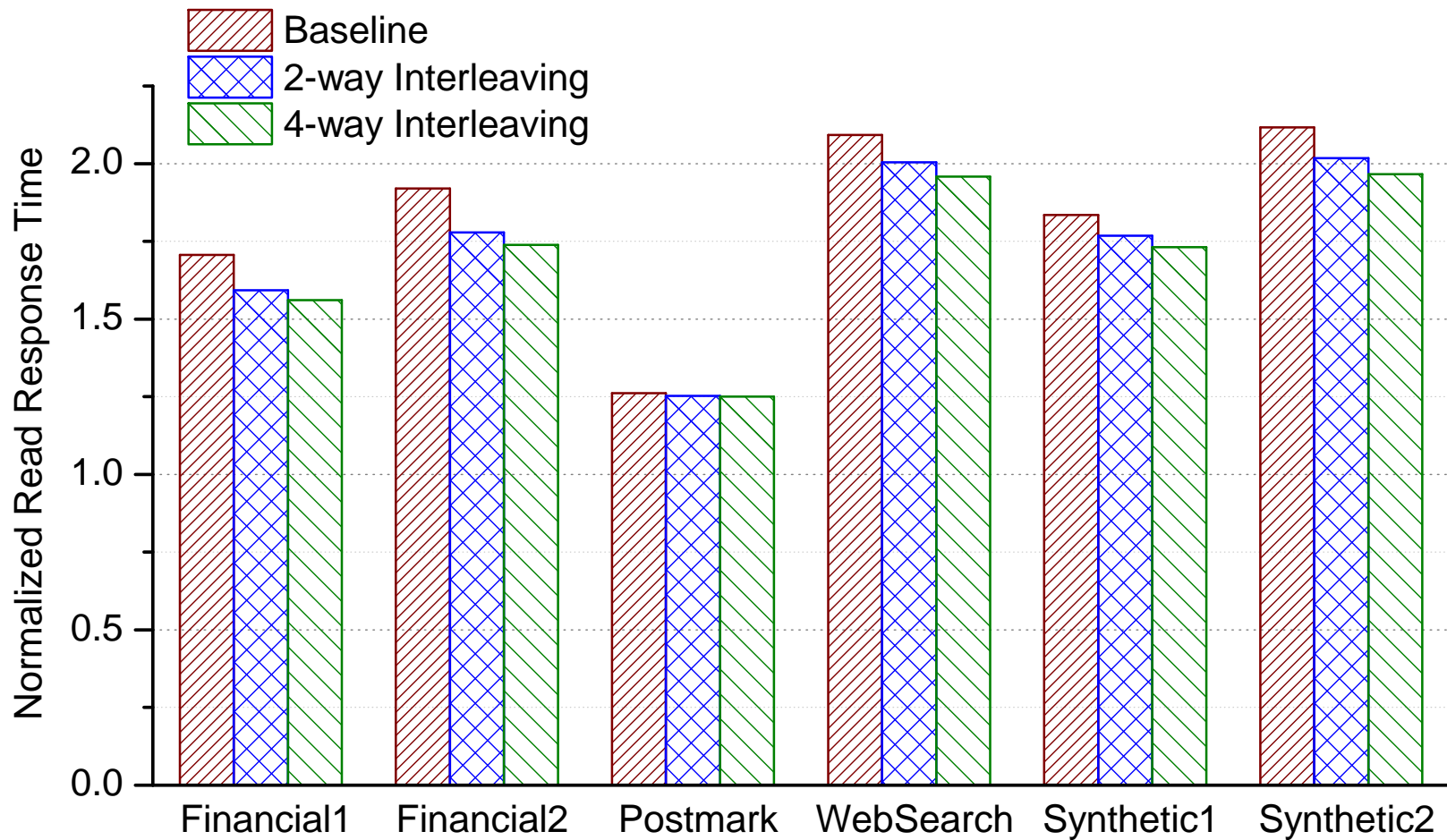
Experimental Results

- Combined look-ahead and progressive sensing



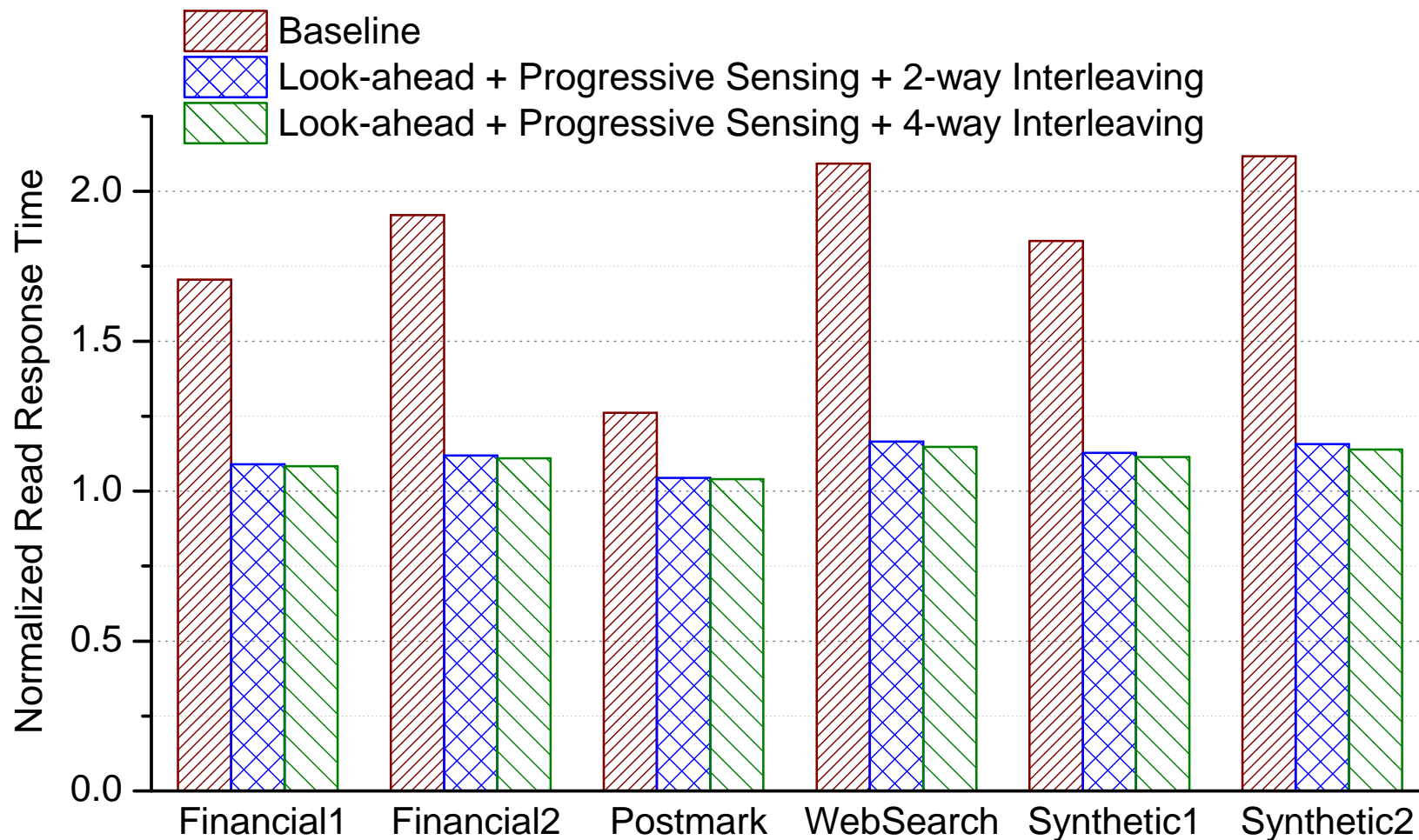
Experimental Results

- Data placement interleaving



Experimental Results

- Aggregated read response time latency reduction



Experimental Results

- Overhead
 - Higher read energy consumption
 - Complicating the controller design
 - Write amplification caused by interleaving

Conclusion

- Increased noise in NAND flash memory caused by technology scaling is a main reason for increasingly high error rates in SSD
- Conventional ECC, such as BCH, does not have sufficient ability to make error code corrections
- LDPC is a strong ECC candidate for future SSDs to address its reliability issues under high noises
- We proposed three techniques to make LDPC work effectively in SSDs
- With LDPC-in-SSD, SSD can continue to increase its capacity, retain a high reliability, and reduce its prices.